FQP6N25

250V N-Channel MOSFET

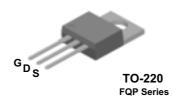
General Description

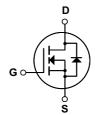
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supply.

Features

- 5.5A, 250V, $R_{DS(on)}$ = 1.0 Ω @V_{GS} = 10 V Low gate charge (typical 6.6 nC)
- Low Crss (typical 7.5 pF)
- Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQP6N25	Units	
V _{DSS}	Drain-Source Voltage		250	V	
I _D	Drain Current - Continuous (T _C = 25°	C)	5.5	А	
	- Continuous (T _C = 100°C)		3.5	А	
I _{DM}	Drain Current - Pulsed	(Note 1)	22	А	
V _{GSS}	Gate-Source Voltage		± 30	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	75	mJ	
I _{AR}	Avalanche Current	(Note 1)	5.5	А	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	6.3	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns	
P_D	Power Dissipation (T _C = 25°C)		63	W	
	- Derate above 25°C		0.5	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		1.98	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	250			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°	С	0.19		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 250 V, V _{GS} = 0 V			1	μΑ
200		V _{DS} = 200 V, T _C = 125°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250 μA	3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 2.75 A		0.82	1.0	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 50 V, I _D = 2.75 A (Note	4)	2.6		S
C _{oss}	Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		50 7.5	65 10	pF pF
C _{rss}	Reverse Transfer Capacitance			7.5	10	pF
Switchi	ng Characteristics					
$t_{d(on)}$	Turn-On Delay Time	V _{DD} = 125 V, I _D = 5.5 A,		8	25	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		65	140	ns
t _{d(off)}	Turn-Off Delay Time			7.5	25	ns
t _f	Turn-Off Fall Time	(Note 4,	5)	30	70	ns
Qg	Total Gate Charge	V _{DS} = 200 V, I _D = 5.5 A,		6.6	8.5	nC
Q_{gs}	Gate-Source Charge	V _{GS} = 10 V		1.74		nC
Q_{gd}	Gate-Drain Charge	(Note 4,	5)	3.4		nC
Drain-S	ource Diode Characteristics a	nd Maximum Ratings			1	I
l _S	Maximum Continuous Drain-Source Diode Forward Current				5.5	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F				22	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 5.5 \text{ A}$			1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_{S} = 5.5 \text{ A,}$ $dI_{F} / dt = 100 \text{ A/}\mu\text{s}$ (Note		125		ns

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 4.0mH, I_{AS} = 5.5A, V_{DD} = 50V, R_G = 25 Ω, Starting T_J = 25°C 3. I_{SD} \leq 5.5A, di/dt \leq 300A/μs, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300μs, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

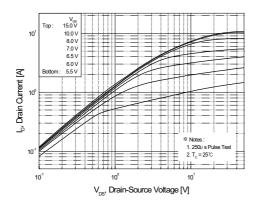


Figure 1. On-Region Characteristics

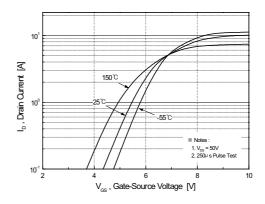


Figure 2. Transfer Characteristics

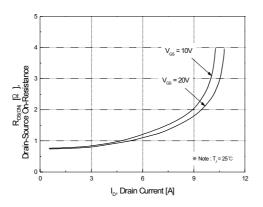


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

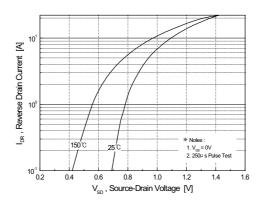


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

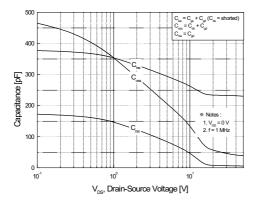


Figure 5. Capacitance Characteristics

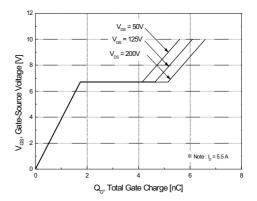
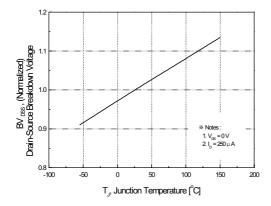


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)



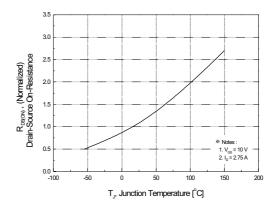
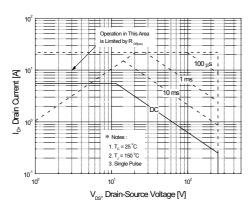


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



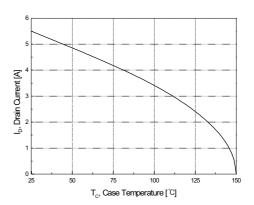


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

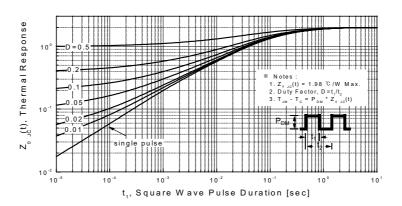
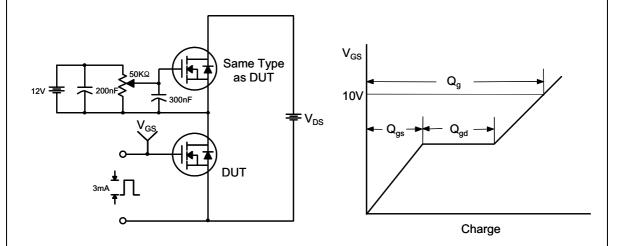


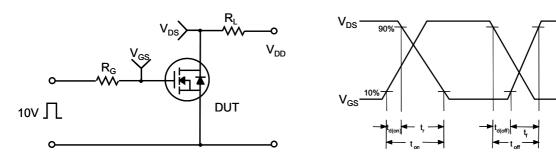
Figure 11. Transient Thermal Response Curve

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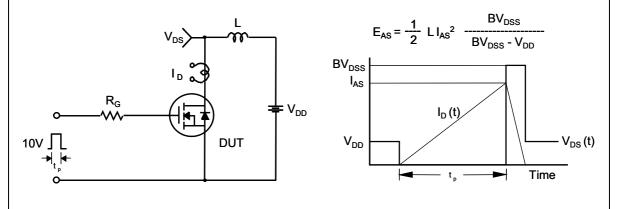
Gate Charge Test Circuit & Waveform



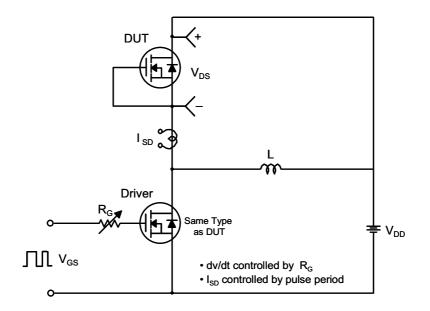
Resistive Switching Test Circuit & Waveforms

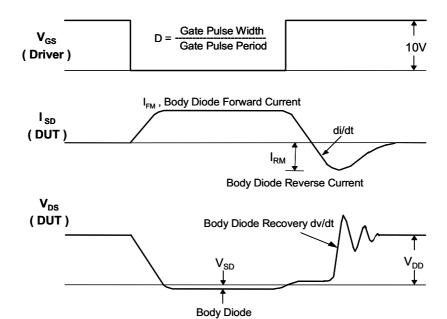


Unclamped Inductive Switching Test Circuit & Waveforms



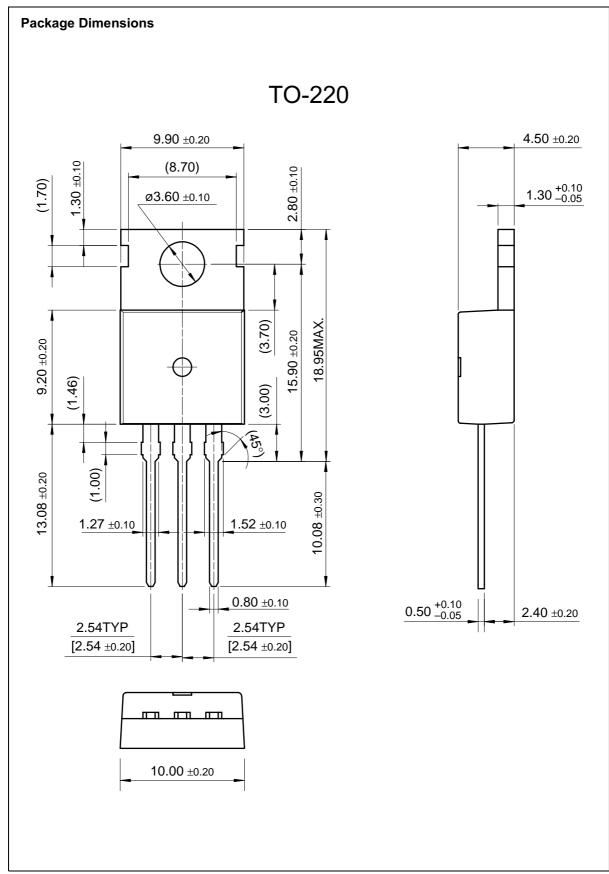
Peak Diode Recovery dv/dt Test Circuit & Waveforms





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Forward Voltage Drop



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